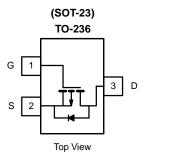
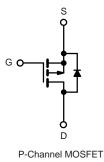


## **QS6U24-VB** Datasheet

# P-Channel 30 V (D-S) MOSFET

PRODUC	CT SUMMARY		
V <sub>DS</sub> (V)	R <sub>DS(on)</sub> (Ω) Typ.	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ.)
	0.046 at V <sub>GS</sub> = - 10 V	- 5.6	
- 30	0.049 at V <sub>GS</sub> = - 6 V	- 5	11.4 nC
	0.054 at V <sub>GS</sub> = - 4.5 V	-4.5	





#### **FEATURES**

- Trench Power MOSFET
- 100 % R<sub>g</sub> Tested ٠



#### **APPLICATIONS**

- For Mobile Computing
  - Load Switch
  - Notebook Adaptor Switch
  - DC/DC Converter

Parameter		Symbol	Limit	Unit
Drain-Source Voltage		V <sub>DS</sub>	- 30	V
Gate-Source Voltage		V <sub>GS</sub>	± 20	V
Continuous Drain Current (T - 150 °C)	T <sub>C</sub> = 25 °C		- 5.6	
	T <sub>C</sub> = 70 °C	1.	- 5.1	
Continuous Drain Current ( $T_J = 150 \ ^{\circ}C$ )	T <sub>A</sub> = 25 °C	I <sub>D</sub>	- 5.4 <sup>b,c</sup>	
	T <sub>A</sub> = 70 °C	1 –	- 4.3 <sup>b,c</sup>	А
Pulsed Drain Current (t = 100 µs)	1	I <sub>DM</sub>	- 18	
Continous Source-Drain Diode Current	T <sub>C</sub> = 25 °C		- 2.1	
Continous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	- 1 <sup>b,c</sup>	
	T <sub>C</sub> = 25 °C		2.5	
Movimum Dower Dissinction	T <sub>C</sub> = 70 °C		1.6	W
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	1.25 <sup>b,c</sup>	VV
	T <sub>A</sub> = 70 °C	1 –	0.8 <sup>b,c</sup>	
Operating Junction and Storage Temperature	e Range	T <sub>J</sub> , T <sub>stq</sub>	- 55 to 150	°C

#### THERMAL RESISTANCE RATINGS Parameter Symbol Typical Maximum Unit Maximum Junction-to-Ambient<sup>b,d</sup> $t \le 5 s$ R<sub>thJA</sub> 75 100 °C/W Maximum Junction-to-Foot (Drain) 40 50 Steady State $\mathsf{R}_{\mathsf{thJF}}$

Notes:

a. Based on  $T_C = 25 \text{ °C}$ . b. Surface mounted on 1" x 1" FR4 board.

c. t = 5 s.

d. Maximum under steady state conditions is 166 °C/W.

Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 V, I_D = -250 \mu A$	- 30			V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	l <sub>D</sub> = - 250 μA		- 19		m)//9	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	$I_D = -250 \mu$ A		4		mV/º	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}$ , $I_D = -250 \ \mu A$	- 0.5		- 2.0	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
Zerra Octo Malta na Davia Oramant	1	$V_{DS} = -30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			- 1		
Zero Gate Voltage Drain Current	IDSS	V <sub>DS</sub> = - 30 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			- 5	5 µA	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \le$ - 5 V, $V_{GS}$ = - 10 V	- 2.5			A	
	. ,	V <sub>GS</sub> =- 10 V, I <sub>D</sub> = - 4.4 A		0.046			
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> =- 6 V, I <sub>D</sub> = - 4 A		0.049		Ω	
		V <sub>GS</sub> =- 4.5 V, I <sub>D</sub> = - 3.6 A		0.054		1	
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = - 15 V, I <sub>D</sub> = - 3.4 A		18		S	
Dynamic <sup>b</sup>		· · · · ·		l .	l .	Į	
Input Capacitance	C <sub>iss</sub>			1295		[	
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> = - 15 V, V <sub>GS</sub> = 0 V, f = 1 MHz		150		pF	
Reverse Transfer Capacitance	C <sub>rss</sub>			130			
		V <sub>DS</sub> = - 15 V, V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 5.4 A		24	36		
Total Gate Charge	Qg			11.4	17		
Gate-Source Charge	Q <sub>gs</sub>	V <sub>DS</sub> = - 15 V, V <sub>GS</sub> = - 4.5 V, I <sub>D</sub> = - 5.4 A		3.4		n	
Gate-Drain Charge	Q <sub>gd</sub>			3.8		-	
Gate Resistance	Rg	f = 1 MHz	1.5	7.7	15.4	S	
Turn-On Delay Time	t <sub>d(on)</sub>		-	13	20		
Rise Time	t <sub>r</sub>	$V_{DD} = -15 \text{ V}, \text{ R}_{1} = 3.5 \Omega$		4	8		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong -4.3 \text{ A}, \text{ V}_{\text{GEN}} = -10 \text{ V}, \text{ R}_{\text{g}} = 1 \Omega$		38	57	-	
Fall Time	t <sub>f</sub>	2 2 9		6	12	-	
Turn-On Delay Time	t <sub>d(on)</sub>			28	42	n	
Rise Time	t <sub>r</sub>	$V_{DD}$ = - 15 V, R <sub>L</sub> = 3.5 $\Omega$		16	24		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \simeq -4.3 \text{ A}, \text{ V}_{\text{GEN}} = -4.5 \text{ V}, \text{ R}_{\text{g}} = 1 \Omega$		30	45		
Fall Time	t <sub>f</sub>			10	20	-	
Drain-Source Body Diode Characteristic					20	I	
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			- 2.1		
Pulse Diode Forward Current ( $t = 100 \mu$ s)	I <sub>SM</sub>	<b>v</b>			- 80	A	
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = - 4.3 A, V <sub>GS</sub> = 0 V		- 0.8	- 1.2	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>	3 - 7 - 63		15	23	n	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			7	14	n	
Reverse Recovery Fall Time	t <sub>a</sub>	$I_F = -4.3 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, \text{T}_J = 25 ^{\circ}\text{C}$		8	14		
	۰a			0		n	

Notes:

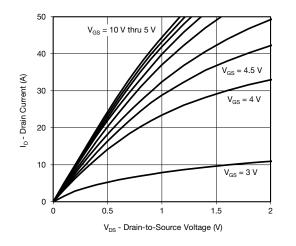
a. Pulse test; pulse width  $\leq$  300 µs, duty cycle  $\leq$  2 %.

b. Guaranteed by design, not subject to production testing.

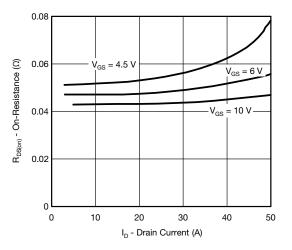
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.







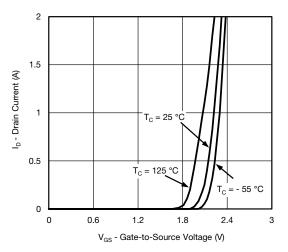




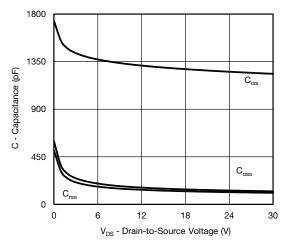
**On-Resistance vs. Drain Current** 



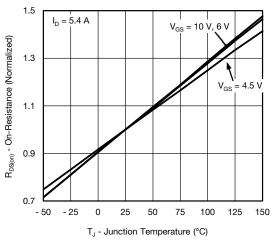
**Gate Charge** 



**Transfer Characteristics** 



Capacitance



**On-Resistance vs. Junction Temperature** 

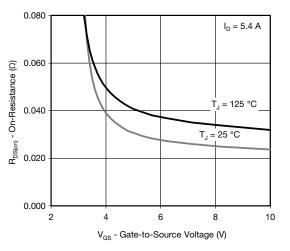




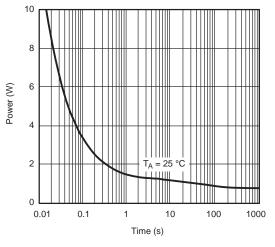




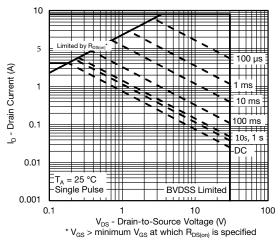
Threshold Voltage



On-Resistance vs. Gate-to-Source Voltage

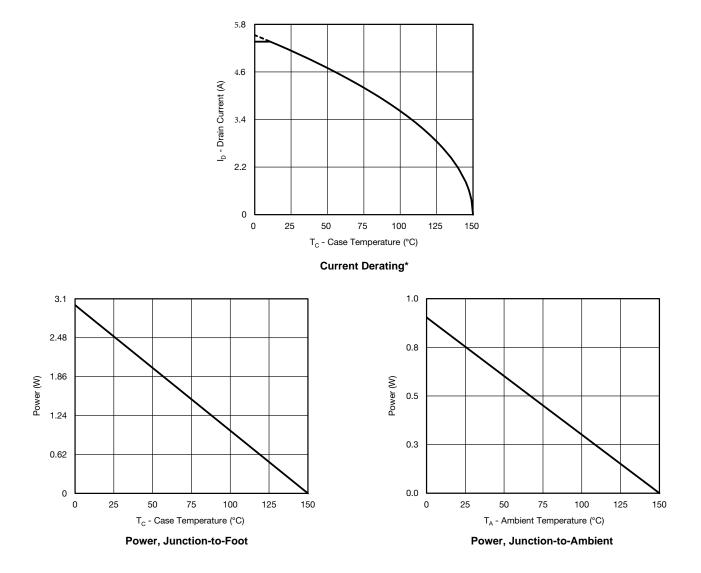


Single Pulse Power (Junction-to-Ambient)



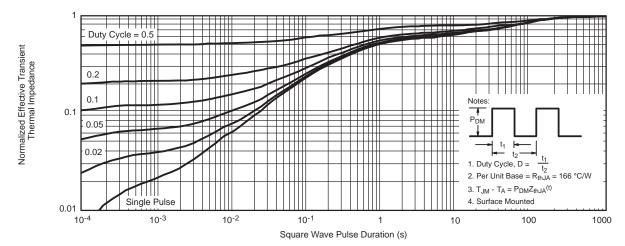
Safe Operating Area, Junction-to-Ambient



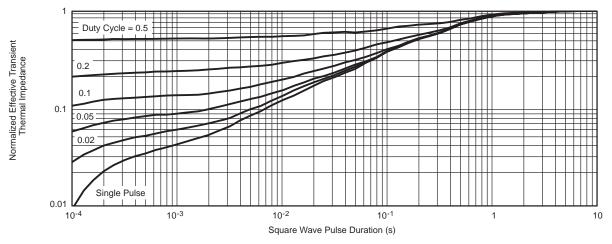


\* The power dissipation  $P_D$  is based on  $T_{J(max.)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





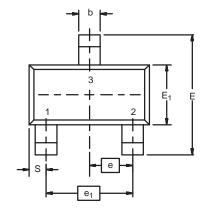
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot



### SOT-23 (TO-236): 3-LEAD







Max   1.12   0.10   1.02   0.50   0.18   3.04   2.64   1.40	Min   0.035   0.0004   0.0346   0.014   0.003   0.110   0.083	Max   0.044   0.004   0.040   0.020   0.007   0.120   0.104		
0.10 1.02 0.50 0.18 3.04 2.64	0.0004 0.0346 0.014 0.003 0.110 0.083	0.004 0.040 0.020 0.007 0.120		
1.02 0.50 0.18 3.04 2.64	0.0346 0.014 0.003 0.110 0.083	0.040 0.020 0.007 0.120		
0.50 0.18 3.04 2.64	0.014 0.003 0.110 0.083	0.020 0.007 0.120		
0.18 3.04 2.64	0.003 0.110 0.083	0.007 0.120		
3.04 2.64	0.110 0.083	0.120		
2.64	0.083			
		0.104		
1.40	0.047			
	0.047	0.055		
0.95 BSC	0.0374 Ref			
1.90 BSC		0.0748 Ref		
0.60	0.016	0.024		
0.64 Ref	0.025	5 Ref		
0.50 Ref		) Ref		
8°	3°	8°		
_	0.64 Ref 0.50 Ref	0.64 Ref 0.025 0.50 Ref 0.026		



#### **RECOMMENDED MINIMUM PADS FOR SOT-23**



Recommended Minimum Pads Dimensions in Inches/(mm)



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